

IN THE DRAWINGS

Per the request of the Examiner, Applicants include herewith a copy of amended FIG. 1 to include the PRIOR ART notation in red ink, attached hereto as Exhibit A.

IN THE CLAIMS

Please cancel claim 21.

Please amend claim 22 as follows:

22. (Amended) The specimen inspection system of claim 12, wherein said pinhole mask is mounted adjacent to the time delay and integration charge coupled device.

C1 (Please amend claim 23 as follows:)

23. (Amended) The specimen inspection system of claim 12, further comprising a focusing lens, wherein said focusing lens receives light energy from said pinhole mask and focuses light energy onto said time delay and integration charge coupled device.
